

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/658,378	NAKAYAMA ET AL.	
	Examiner Tuan Quach	Art Unit 2814	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
257	618-628	1/18/2005	TQ
257	797	1/18/2005	TQ